ON Semiconductor®

Final Product/Process Change Notification

Document # : FPCN22242Z
Issue Date: 11 April 2018

Title of Change:	NCV7471 Datasheet update.
Proposed Changed Material First Ship Date:	11 April 2019 *or earlier upon customer approval.*
Product Category:	Active components – Integrated circuits
Contact information:	Contact your local ON Semiconductor Sales Office or <ondrej.kupcik@onsemi.com>.
Samples:	Contact your local ON Semiconductor Sales Office to place sample order. Sample requests are to be submitted no later than 45 days after publication of this change notification.
Sample Availability Date:	3 April 2018
PPAP Availability Date:	3 April 2018
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office or <Catherine.DeKeukeleire@onsemi.com>
Type of Notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 12 months prior to implementation of the change or earlier upon customer approval. ON Semiconductor will consider this proposed change and it's conditions acceptable, unless an inquiry is made in writing within 45 days of delivery of this notice. To do so, contact <PCN.Support@onsemi.com>.
Data Sheet	Correction of data sheet / errata

Description and Purpose:

Datasheet update:

- I_VS parameter test conditions updated
- I_VCC_CAN parameter test conditions updated
- tSCK_SDOlow limit changed to high limit
- NCV7471DQ5 OPN removed (Announced in PRODUCT DISCONTINUANCE # 20734 (14-Jan-2015))
- MSL level specification added (MSL = 2)

Reason / Motivation for Change:	- Change benefits for customer: Datasheet integrity improved - Risk for late release for customer: The temperature range for parameters specifications (I_VS and I_VCC_CAN current consumptions) limited to 85˚C	
Anticipated impact on fit, form, function, reliability, product safety or manufacturability	The device has been qualified and validated based on the same Product Specification. The device has successfully passed the qualification tests. Potential impacts can be identified, but due to testing performed by ON Semiconductor in relation to the PCN, associated risks are verified and excluded. No anticipated impacts as already discussed and validated by customer.	
Sites Affected:	ON Semiconductor Sites: All Sites	External Foundry/Subcon Sites: None
Marking of Parts/ Traceability of Change:	Affected products will be identified by datecode.	

Reliability Data Summary:

N/A. See reliability data of original PPAP NCV7471.

Electrical Characteristic Summary:

I_VS parameter test conditions updated
- Test condition modified – "Tj ≤ 85˚C" added

I_VCC_CAN parameter test conditions updated
- Test condition modified – "Tj ≤ 85˚C" added

tSCK_SDOlow limit changed to high limit
- Misplaced limit number corrected – moved from Low limit to High limit

List of Affected Standard Parts:

Current Part Number	New Part Number	Qualification Vehicle
NCV7471DQ5R2G	NCV7471DQ5R2G	NCV7471DQ5R2G
NCV7471ADQ5R2G	NCV7471ADQ5R2G	NCV7471ADQ5R2G